FOR IMMEDIATE RELEASE

BT IMAGING INTRODUCES UPGRADED WAFER SORTING CAPABILITIES TO ITS RANGE OF PHOTOLUMINESCENCE IMAGING-BASED WAFER INSPECTION SORTERS.

Sydney, Australia, June 21, 2013 - BT Imaging Pty Ltd, the world’s leading supplier of luminescence-based inspection and quality control systems for the photovoltaic manufacturing industry, today announced upgraded hardware and software capabilities, including a new third-generation of proprietary algorithms, for its range of photoluminescence imaging-based wafer inspection sorters.

The new upgraded system extends the wafer sorting capabilities of the BT Imaging wafer inspection sorters to include both mono-crystalline silicon wafers and high-performance multi-crystalline silicon wafers. In addition, the sorting of standard multi-crystalline wafers has been improved such that wafer quality spread within any individual sorting bin is even further reduced.

“We are very proud of the results produced by our technical team” said Ian Maxwell, CEO, “Our hardware, software and algorithm development teams have been working very closely with trial customers over the last year or so, and the results now speak for themselves. Our focus has very much been to ensure that we can offer our customers a wafer inspection sorter that works for all wafer types and that also adds to their revenues whilst reducing their production costs.”

About BT Imaging

BT Imaging designs and builds manufacturing tools used by manufacturers of photovoltaic bricks, wafers and cells. The company is focused on ‘inspection' manufacturing systems and solutions that are used for quality control, yield enhancement and process control in customer's factories. The company’s suite of inspection systems combines state-of-the-art hardware and software. BT imaging offers a number of product solutions, many using patented photoluminescence imaging technology; these products help our customers increase factory yield and solar cell efficiencies.

Website

www.btimaging.com